Applicant(s)/Patent Under Application/Control No. Reexamination 10/035,387 CHAN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Huy K. Mai 2873 U.S. PATENT DOCUMENTS Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2003/0076575 04-2003 Stappaerts, Eddy A. 359/291 Α US-2003/0025981 02-2003 359/290 В Ishikawa et al. С US-5,652,672 07-1997 Huignard et al. 359/292 US-D Ε US-US-F US-G US-Н USł US-J US-Κ US-L US-FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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